Same-Side Flavor Tagging at CDF

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- Flavor tagging
- Reconstructing the B decays
- Fragmentation track correlations
- Selecting the Same Side Tag
- Measuring the tagger properties

  Efficiency, Dilution, εD^2
- Summary

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Chicago Flavor Seminar

B-flavor tagging

Observation of mixing in a neutral B system (B_d or B_s) relies on determination of production flavor: b or anti-b

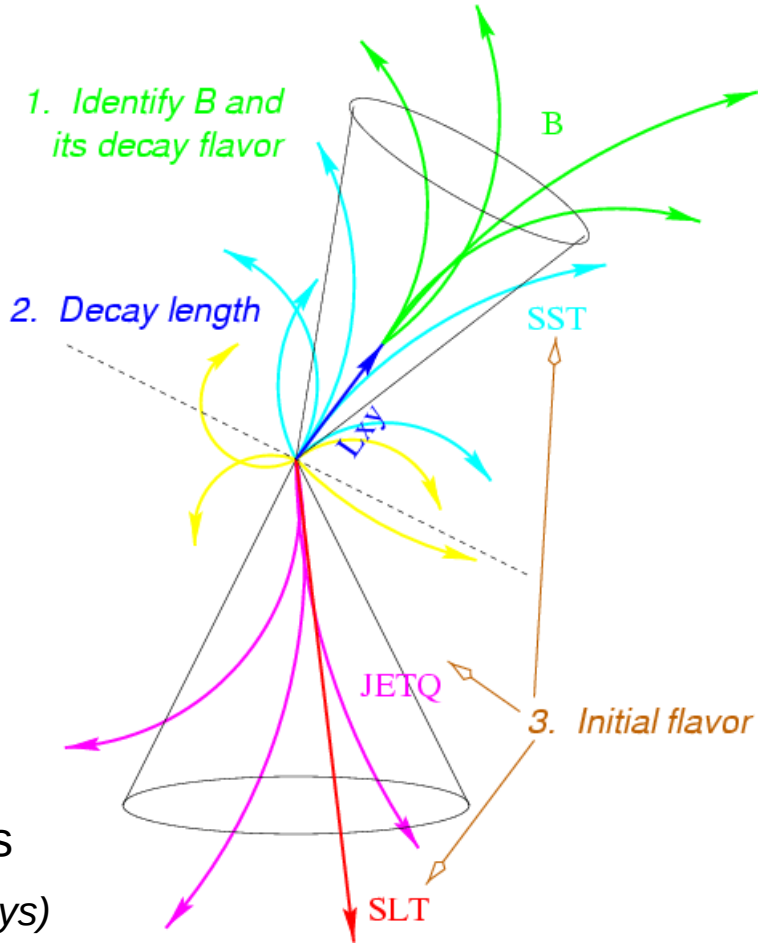
Tagging methods used at CDF:

- Same-Side Tagging (SST)
- Opposite-Side Tagging (JETQ, SLT)

(see I.Kravchenko's talk for details on OST)

Tagger properties are better accessed in fully reconstructed charged B meson decays

(see J.Piedra's talk for SST applied to neutral B decays)



Reconstructing the B decays (1)

$B^+ \rightarrow J/\psi K^+, \quad J/\psi \rightarrow \mu^+ \mu^-$

J/ψ

-$p_T(\mu^{\pm}) > 1.5$ GeV/c

K

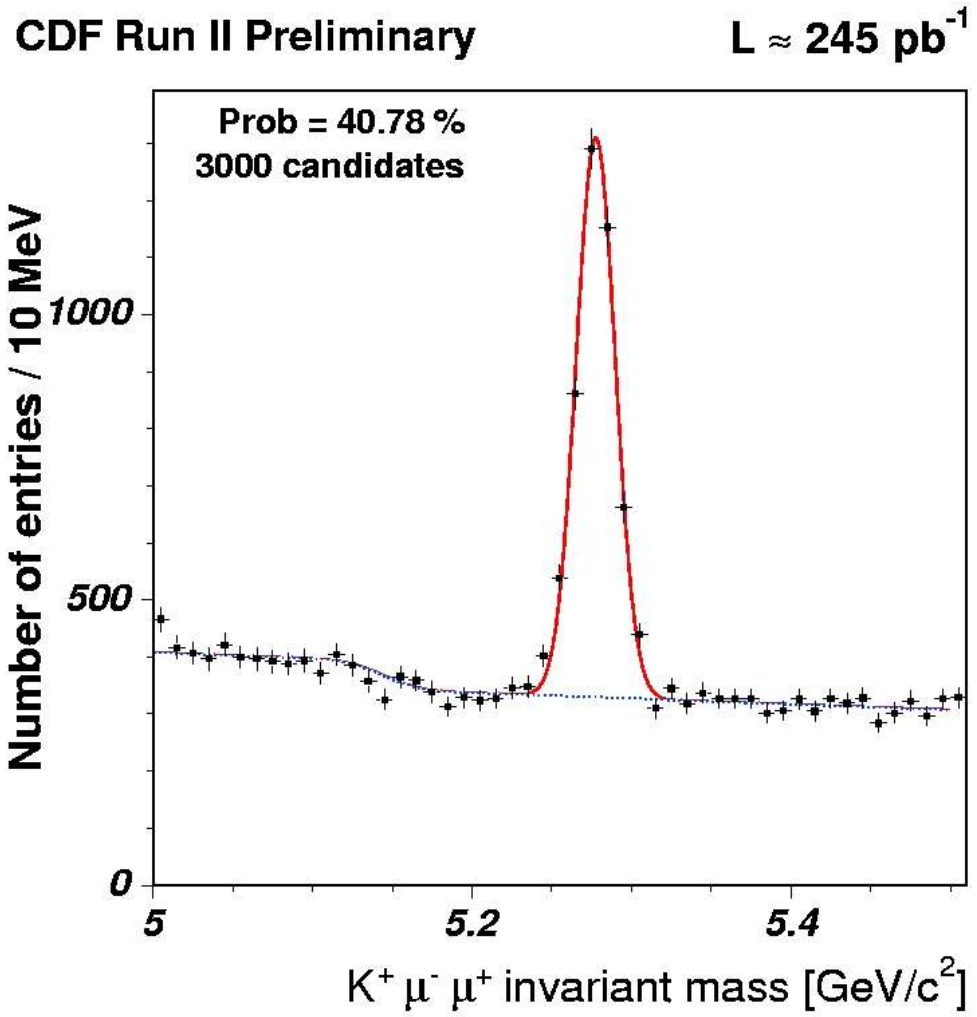
-$p_T > 2$ GeV/c

B

-$p_T > 6.5$ GeV/c

-Vertex probability > 0.1%

-$L_{xy} > 100$ μm



Reconstructing the B decays (2)

$B^+ \to \bar{D}^0 \pi^+ , \quad \bar{D}^0 \to K^+ \pi^-$

D

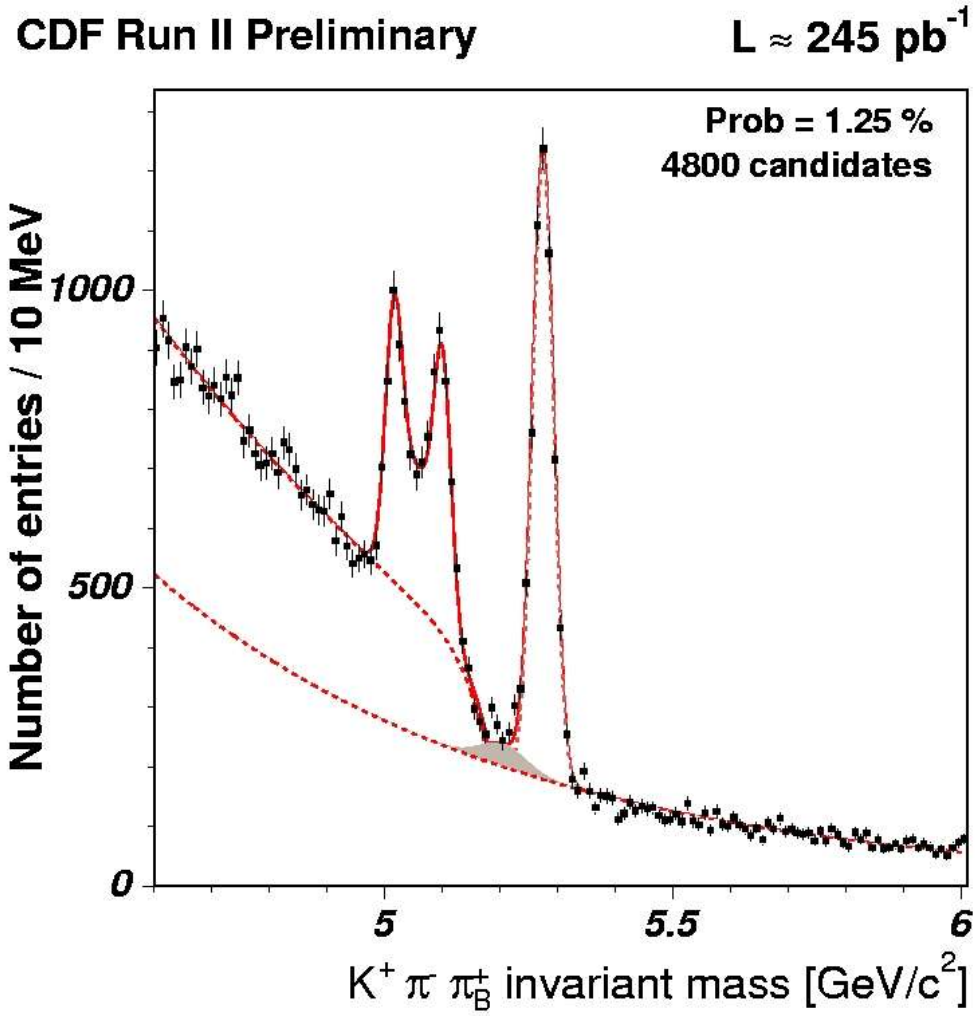
- $\chi^2(r,\phi) < 14$
- $\Delta R(D,\pi_B) < 1.5$

π_B

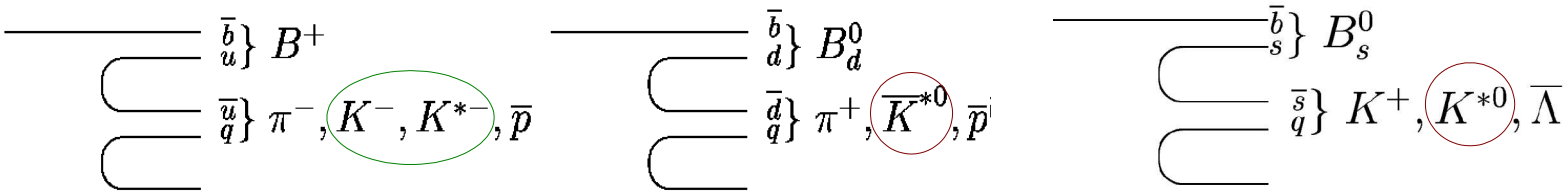
- $P_T > 1.5$ GeV/c

B

- $\chi^2(r,\phi) < 15$
- $|d0| < 80$ μm
- $L_{xy}(B\text{->}D) > -150$ μm
- $L_{xy} > 300$ μm



Fragmentation track correlations



The SST method is based on expected *flavor-charge correlations*:

- between B meson and particles produced in fragmentation
- between B meson and pions coming from B^{**} decays

  B^+(B^-) are accompanied by negative (positive) pions

  B^0($\overline{B^0}$) are accompanied by positive (negative) pions

Mistagging probability for neutral decays is expected to be larger

- tracks from K^* do not contribute in the neutral case

Selecting the Same Side Tag

The identification of the flavor of a neutral B meson can make use of hadrons produced nearby in phase space. ***M.Gronau, J.Rosner, Phys.Rev. D49 (1994) 254-264***

Consider tracks:

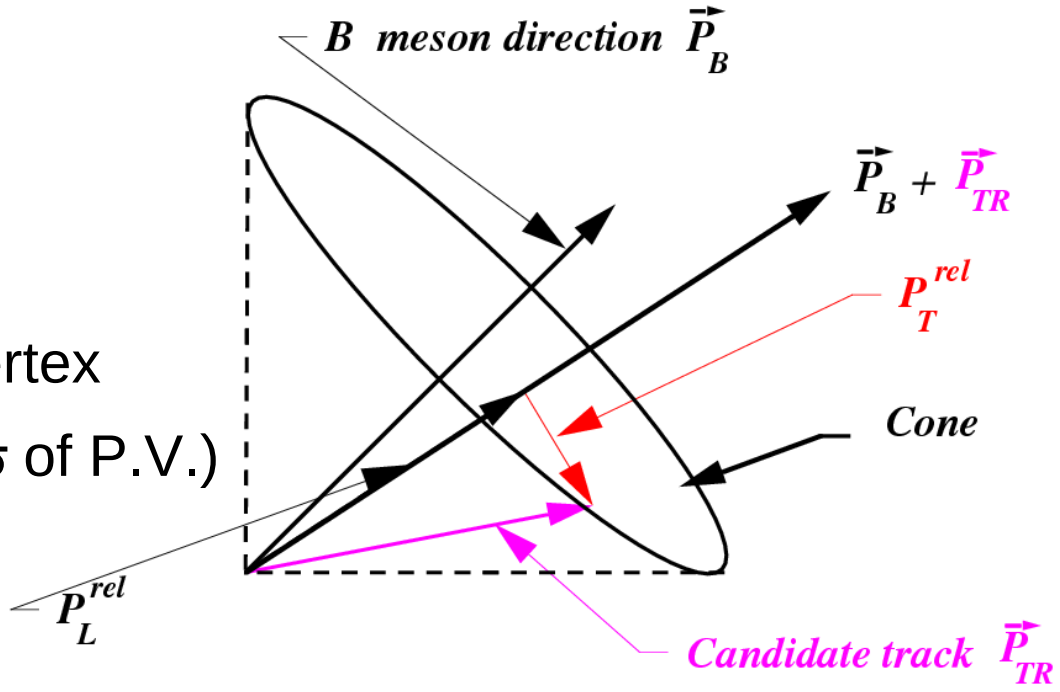
- close to the B meson

$$\Delta R \equiv \sqrt{\Delta\eta^2 + \Delta\phi^2} < 0.7$$

- p_T > 350 MeV
- originating from Primary Vertex

  (impact parameter within 3σ of P.V.)
- track quality cuts
- multiple track candidates:

→ select track with minimum p_T^{rel}



Measuring the tagger properties

Each B candidate is assigned to one of 3 classes:

- Right-Sign (RS), if *production* flavor = *decay* flavor
- Wrong-Sign (WS), if *production* flavor ≠ *decay* flavor
- Not Tagged (NT), if no SST tag track candidates are found

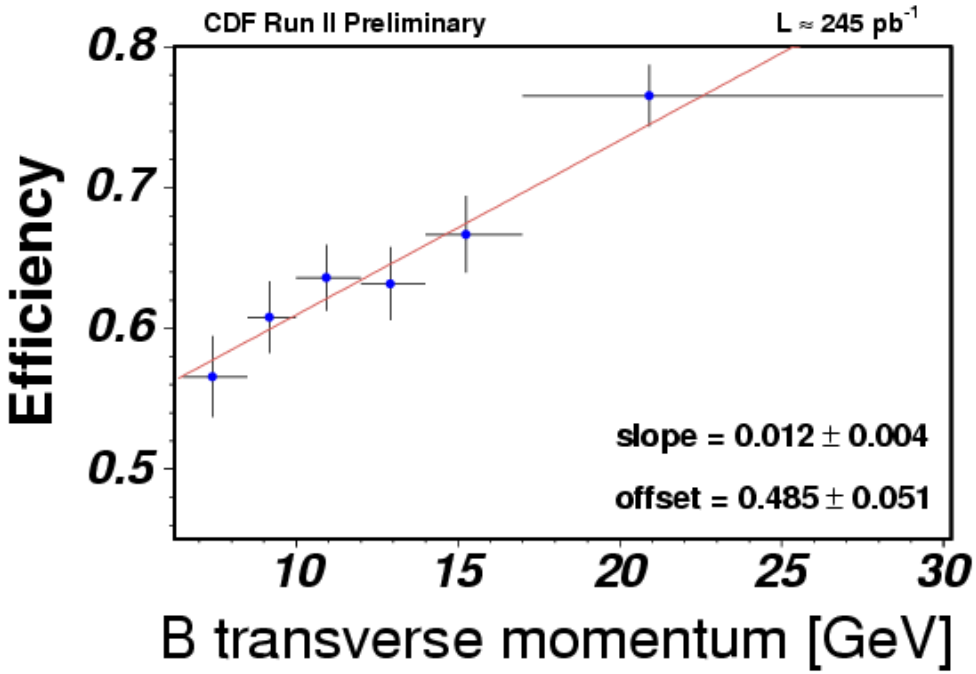
- Definition of tagger properties:

- Efficiency: $$\epsilon = \frac{N_{tagged}}{N_{total}} = \frac{N_{RS} + N_{WS}}{N_{RS} + N_{WS} + N_{NT}}$$

- Dilution: $$D = 1 - 2P_{mistag} = \frac{N_{RS} - N_{WS}}{N_{RS} + N_{WS}}$$

Sample is further subdivided in bins of $\mathbf{p_T}$ and **ct** of the B meson

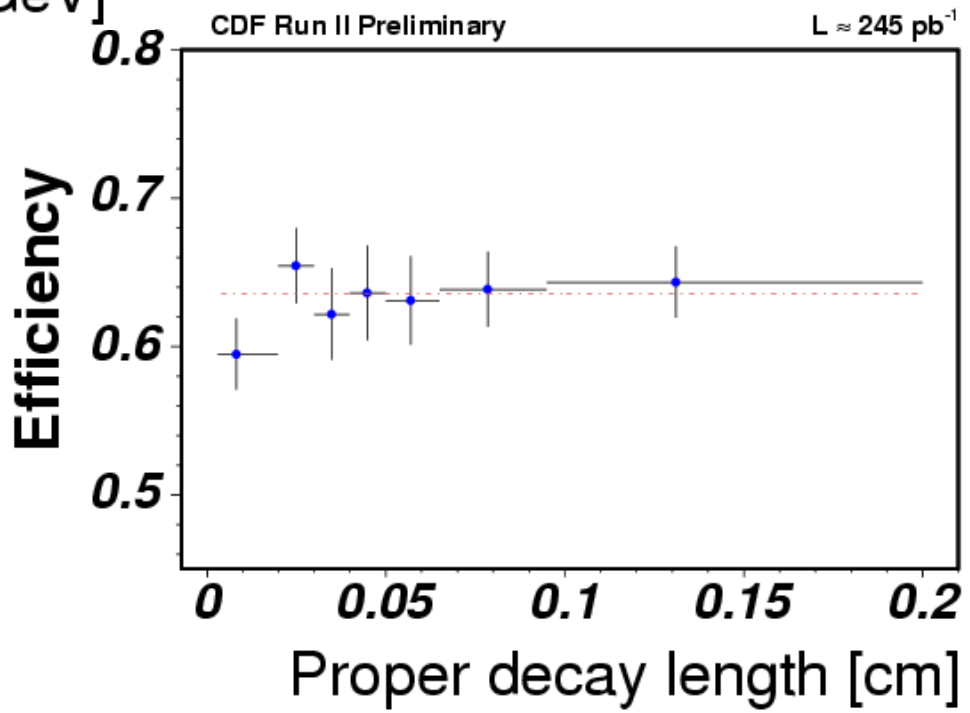
Same-Side Tagger efficiency (1)



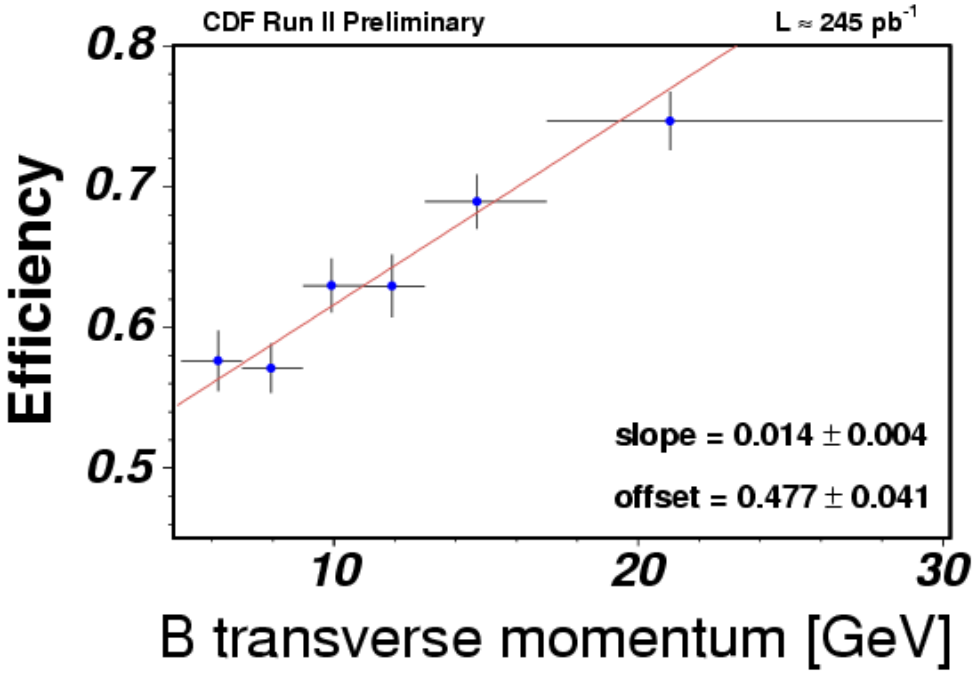
$\varepsilon = 63.5 \pm 1.2\ \%$

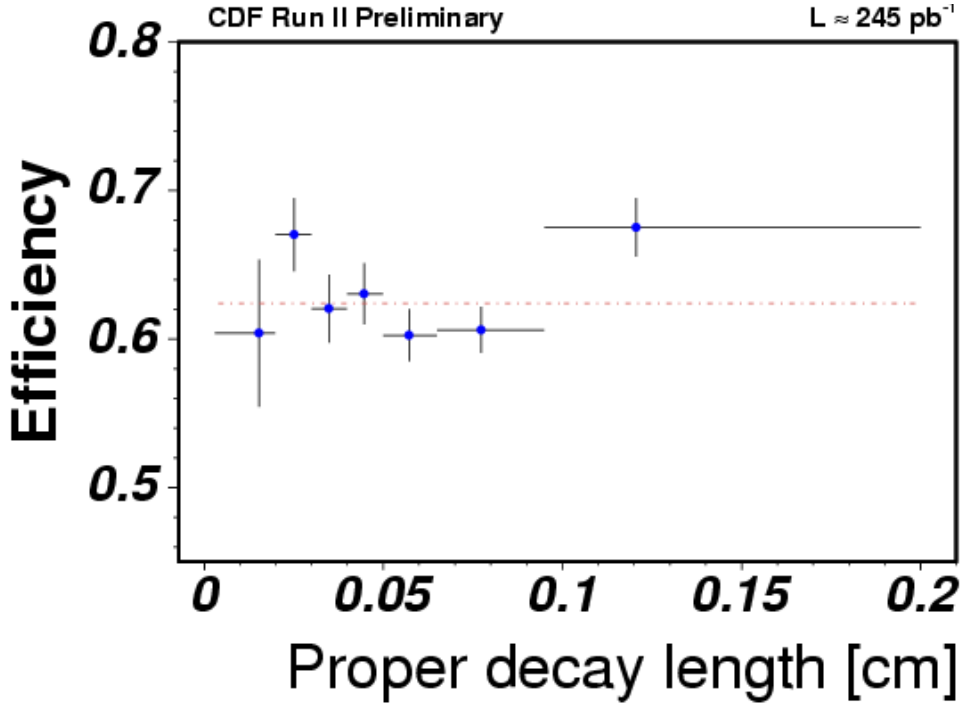
$B^{\pm} \rightarrow J/\psi\, K^{\pm}$

$[J/\psi \rightarrow \mu^{+}\ \mu^{-}]$



Same-Side Tagger efficiency (2)

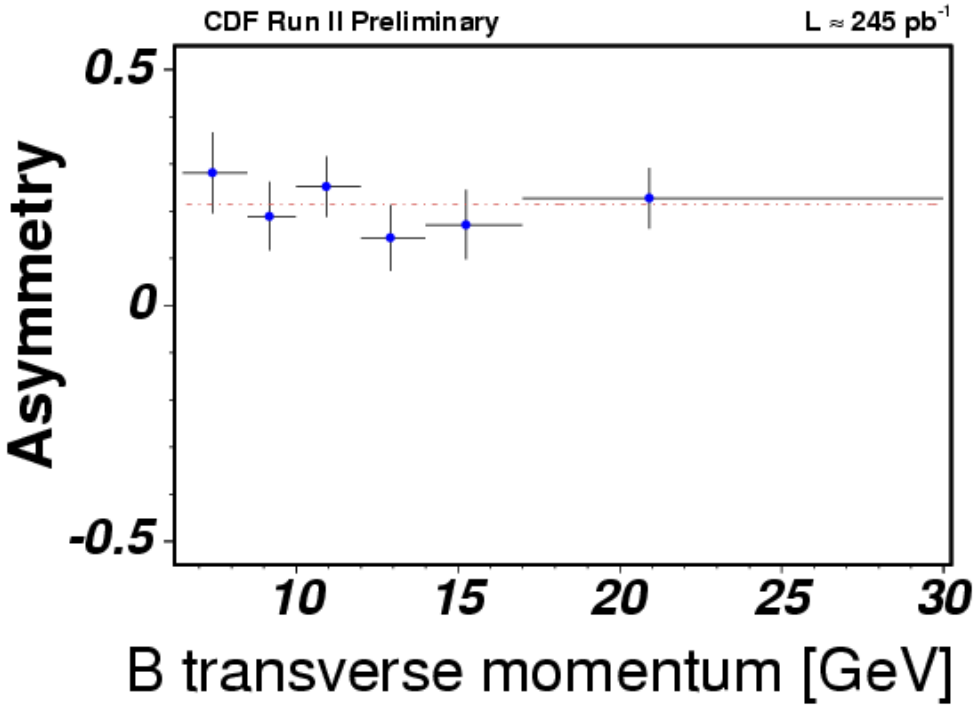




$\varepsilon = 62.4 \pm 0.8\ \%$

$B^+ \to \bar{D}^0 \pi^+$

$[\bar{D}^0 \to K^+ \pi^-]$

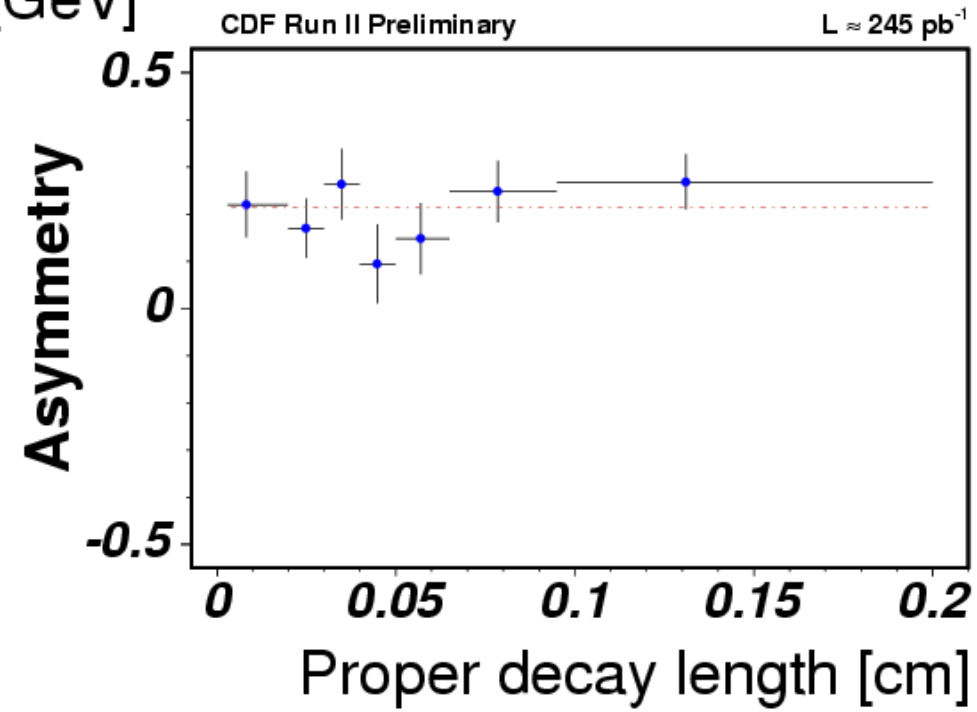


Same-Side Tagger dilution (1)

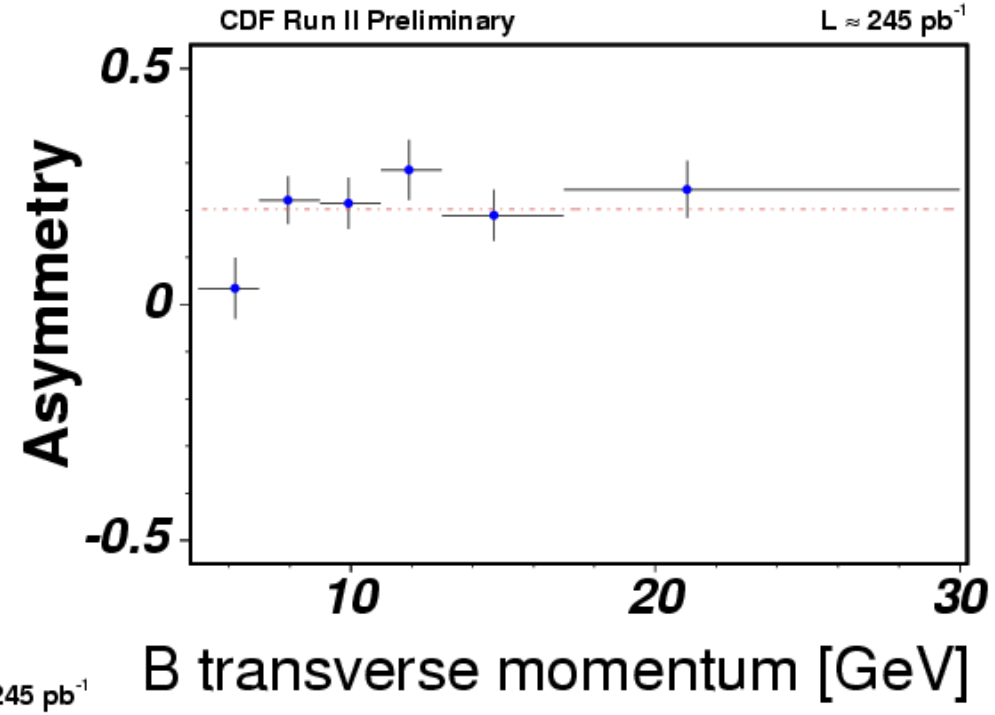
$D = 22.2 \pm 3.4\ \%$

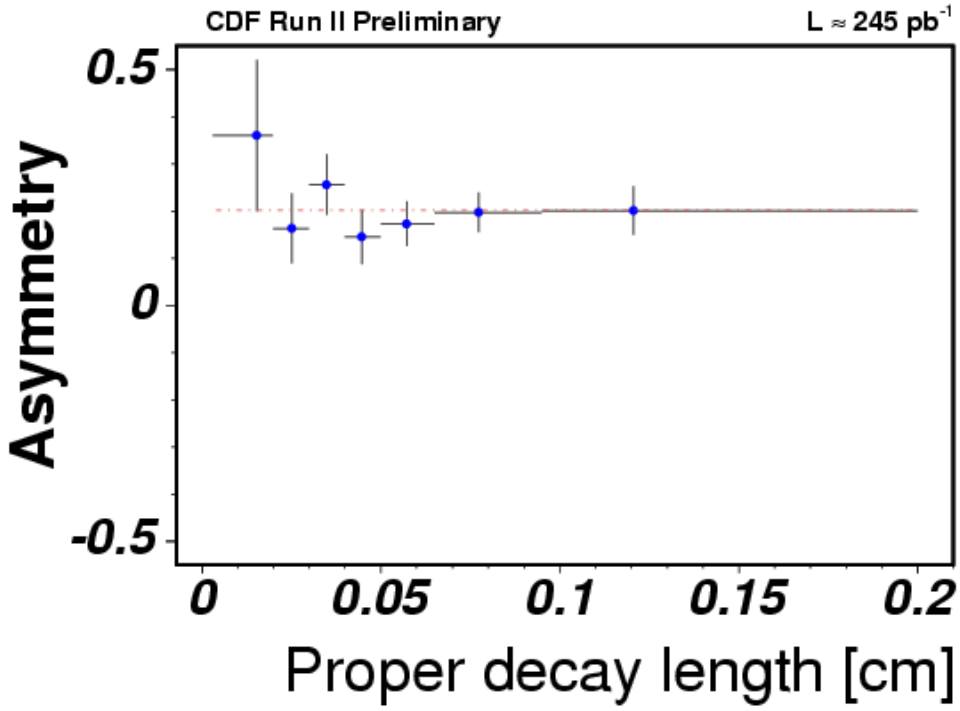
$B^{\pm} \rightarrow J/\psi\, K^{\pm}$

$[J/\psi \rightarrow \mu^{+}\ \mu^{-}]$



Same-Side Tagger dilution (2)





D = 20.2 ± 2.4 %

$$B^+ \to \bar{D}^0 \pi^+$$

$$[\bar{D}^0 \to K^+ \pi^-]$$

Summary

- The Same-Side Tagging technique has been studied in two fully reconstructed charged B meson decays
- The observed behavior and tagger properties agree well for the studied decays
- The measured tagger properties for charged decays is

  $\varepsilon(B^+) = 62.7 \pm 0.7$ (stat.) %

  $D(B^+) = 21.2 \pm 2.0$ (stat.) %

  $\varepsilon D^2(B^+) = 2.8 \pm 0.5$ (stat.) % $\neq \varepsilon D^2(B^0) \neq \varepsilon D^2(B_S)$

- Further SST studies under way towards B_S mixing
  - Optimize tagger for B^0 mixing
  - Reproduce SST with Monte Carlo
  - Include particle identification (TOF, dE/dx)